


<b>Search Notes</b>  	<b>Application/Control No.</b>  10500210	<b>Applicant(s)/Patent Under Reexamination</b>  YAMASHITA ET AL.
	<b>Examiner</b>  WEN-YING P CHEN	<b>Art Unit</b>  2871

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
reviewed previously cited references	7/16/2008	wpc
consulted primary examiner Andrew Schechter regarding the submitted affidavit	7/16/2008	wpc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner